

RoHS COMPLIANT

SIR468DP-T1-GE3-VB Datasheet N-Channel 30 V (D-S) MOSFET

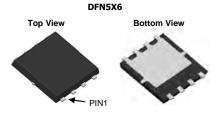
PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)		
30	0.003 at V _{GS} = 10 V	120	71 nC		
	0.005 at V _{GS} = 4.5 V	90	71110		

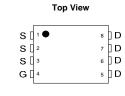
FEATURES

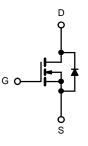
- Trench Power MOSFET
- 100 % R_g and UIS Tested ٠

APPLICATIONS

- Notebook PC Core
- VRM/POL •







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	30	V		
Gate-Source Voltage	V _{GS}	± 20			
	T _C = 25 °C		120 ^{a, e}		
Continuous Drain Current (T 175 °C)	T _C = 70 °C		90 ^e		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	21 ^{b, c}	A	
	T _A = 70 °C		20.8 ^{b, c}	^	
Pulsed Drain Current	I _{DM}	250			
Avalanche Current Pulse	1 0.1 ml l	I _{AS}	56		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	60	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	80 ^{a, e}	A	
Continuous Source-Drain Diode Current	T _A = 25 °C	15	76 ^{b, c}		
	T _C = 25 °C		210 ^a		
Maximum Bower Dissipation	T _C = 70 °C	PD	155	w	
Maximum Power Dissipation	T _A = 25 °C	'D	35 ^{b, c}	vv	
	T _A = 70 °C		13 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t \leq 10 s		41	50	°C/W		
Maximum Junction-to-Case	Ise Steady State		0.7	0.9	0/10		

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under steady state conditions is 90 °C/W.

e. Calculated based on maximum junction temperature. Package limitation current is 80 A.

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SPECIFICATIONS (T _J = 25 °C, unless otherwise noted) Parameter Symbol Test Conditions Min . Typ. Max.							
Static	Symbol	Test conditions	IVIII .	тур.	IVIAX.	Unit	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	30	1		V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.5			
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30$ V, $V_{GS} = 0$ V, $T_{J} = 55$ °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 V, V_{GS} = 10 V$	80			A	
		V _{GS} = 10 V, I _D = 32 A		0.003		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 29 A		0.005			
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 32 A		130		S	
Dynamic ^b							
Input Capacitance	C _{iss}				3200		
Output Capacitance	C _{oss}	V_{DS} = 12.5 V, V_{GS} = 0 V, f = 1 MHz			1025	pF	
Reverse Transfer Capacitance	C _{rss}				970		
Total Gate Charge		$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 32 \text{ A}$			71	nC	
	Q _g				61.5		
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 29 A			34		
Gate-Drain Charge	Q _{gd}				29		
Gate Resistance	Rg	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.555 Ω		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 27$ A, V_{GEN} = 10 V, R_g = 1 Ω		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83		
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_{D} \cong$ 24 A, V_{GEN} = 4.5 V, R_{g} = 1 Ω		55	83		
Fall Time	t _f			12	18		
Drain-Source Body Diode Characteristic	cs					-	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			80	A	
Pulse Diode Forward Current ^a	I _{SM}				100		
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 20 A, di/dt = 100 A/μs, T _J = 25 °C		70.2	105	nC	
Reverse Recovery Fall Time	t _a	$r_{\rm F} = 20$ A, $a_{\rm H}a_{\rm I} = 100$ A/ μ s, $r_{\rm J} = 20$ C		27			
Reverse Recovery Rise Time t _b				25		ns	

Notes:

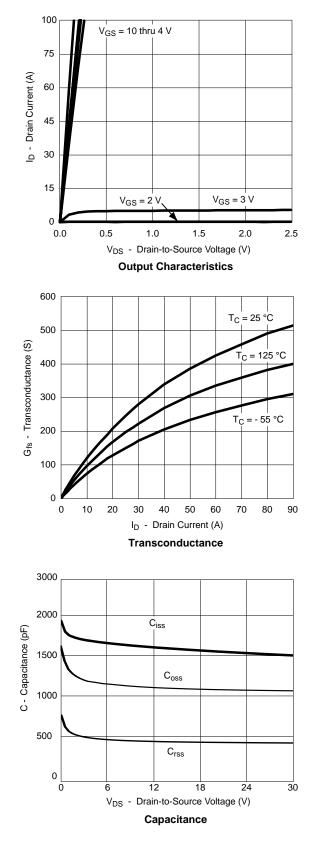
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

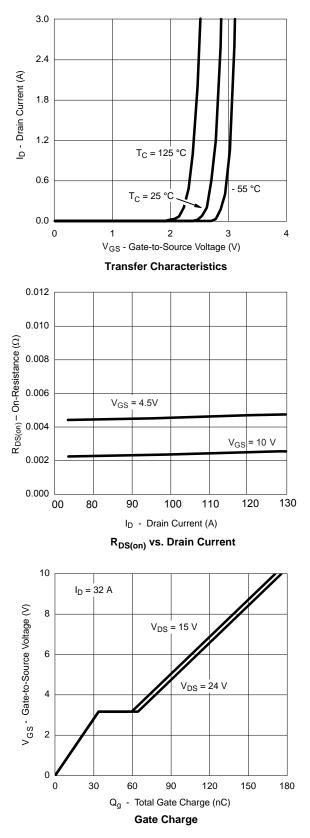
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

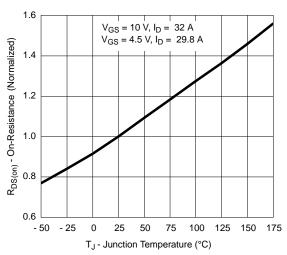


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



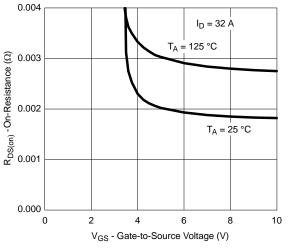


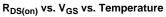




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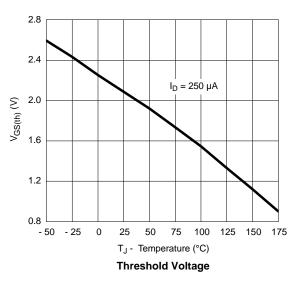


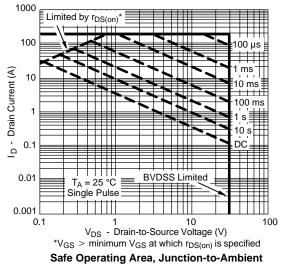




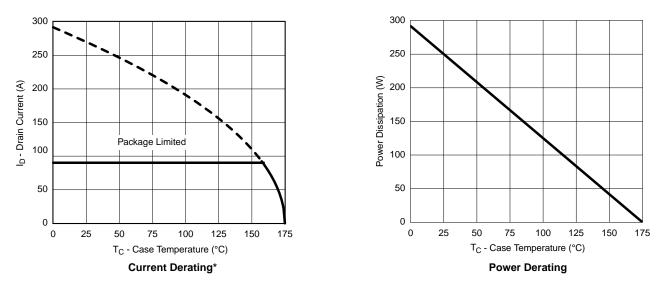












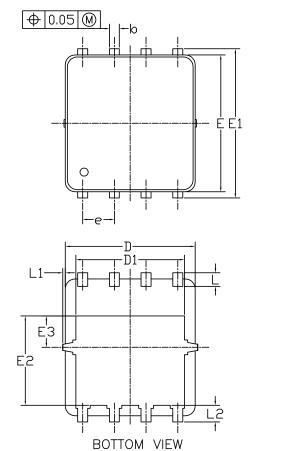
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

* The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

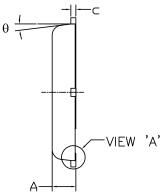


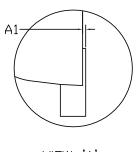
Normalized Thermal Transient Impedance, Junction-to-Case



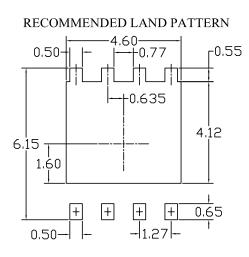


DFN5x6_8L_EP1_P PACKAGE OUTLIN





<u>VIEW 'A'</u> (SCALE 5:1)



	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.85	0.95	1.00	0.033	0.037	0.039	
Al	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
с	0.15	0.20	0.25	0.006	0.008	0.010	
D	5.10	5.20	5.30	0.201	0.205	0.209	
D1	4.25	4.35	4.45	0.167	0.171	0.175	
Е	5.45	5.55	5.65	0.215	0.219	0.222	
E1	5.95	6.05	6.15	0.234	0.238	0.242	
E2	3.525	3.625	3.725	0.139	0.143	0.147	
E3	1.175	1.275	1.375	0.046	0.050	0.054	
e	1.27 BSC			0.050 BSC			
L	0.45	0.55	0.65	0.018	0.022	0.026	
L1	0		0.15	0		0.006	
L2	0.68 REF			0.027 REF			
θ	0°		10°	0°		10°	

NOTE

UNIT: mm

 PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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